

PCN Number: CO-23764	Contact: Elizabeth La Greca			
Date Issued: Jun 18th, 2019	Title: Director, Sales Operations			
PCN Effective Date: September 18th, 2019	Phone: 1-858-795-0106			
Product(s) Affected: PE4151	Email: pcn@psemi.com			
Sample Availability: Jun 18th, 2019	1			
Change Control Board Approval #: CO-23764				
Change Category:				
Wafer Fabrication Process	Shipping/Labeling			
Design/Mask Change	Equipment			
Singulation Process	Material			

Product Specification
Product End of Life

Other - Ordering codes change

Assembly Process

Electrical Test

Manufacturing Site

Purpose of Change:

To enable usage of Lapis in Japan as the wafer fabrication site for the PE4151.

Description of Change:

This is a notification to advise our customers that pSemi is transferring PE4151. pSemi has been working to transfer products from Silanna fab in Australia to Lapis fab in Japan to ensure continuous supply. Silanna and Lapis are qualified pSemi fabs.

Starting <u>September 18th</u>, the PE4151 shipped to customers will be supplied from either Silanna or Lapis wafers. Lapis will be the primary wafer fabrication site for the PE4151.

PE4151 material has been qualified with no change to form, fit, function or reliability.

Ordering code changes:

Original ordering codes (Silanna): PE4151MLAA-Z; EK4151-01 New ordering codes (Lapis): PE4151B-Z; EK4151-02

pSemi manages inventory on a First-In First-Out (FIFO) basis. For the exact timing of the order code change, please contact your account rep. or <u>accountrep@psemi.com</u>.



Customer Acknowledgement of Receipt:

Change Denied	Name:	
(Include explanation in comments section below)	Title:	
Change Approved	Company:	
	Date:	
	Signature:	
Customer Comments:		



Appendix A – Reliability Qualification Summary



PE4151

Reliability Summary Report

Part Number(s):	PE4151	Product Family:	Mixer	
Package Type:	10L MSOP	MSL Rating:	MSL1	
Technology Platform:	chnology Platform: ULTRACMOS [®] 2			
Reliability Summary:	Based on the results of reliability testing, the PE4151 has met the relia- bility requirements for Production.			

Table 1: Product Design Reliability Results

Test #	Test Performed	TEST METHOD/ Conditions	Duration	Sample Size	Result
1	High Temperature Operating Life (HTOL)	JESD22-A108; VDD= 3.1 V; T _A = T _J = 150 °C;	500 Hrs.	1 lot x 77	Pass
2	ESD Human Body Model (HBM)	MIL-STD-883 Model 3015.7 (All pins)	1.0 kV	1 lot x 3	Pass

DOC-84190 Rev 1

pSemi Confidential







PE4151

Reliability Summary Report

Table 2: Package Reliability Results

Test	Test Performed	TEST METHOD/ Conditions	Duration	Sample Size	Result
3	High Temperature Storage Life (HTSL)	JESD22-A103; T _a = 150°C	1,000 hrs.	119	Pass
4	Highly Accelerated Stress Test (HAST)	JESD22-A110; T _a = 130°C, RH= 85%; VDD= 3.3 V	168 hrs.	45	Pass
5	Autoclave (AC)	JESD22-A102; T _a = 121°C; RH= 100%; 2.023 atm	96 hrs.	45	Pass
6	Temperature Cycling (TC)	JESD22-A104; T _a = -65°C to +150°C	500 cycs.	45	Pass

Table 3: Package Assembly Level Reliability Results

Test #	Test Performed	TEST METHOD/ Conditions	Duration	Sample Size	Result
7	Wire Bond Pull	AEC-Q100-001 / Subcon specs.	-	40	Pass
8	Physical Dimensions	JESD22-B100 / Subcon specs.	-	40	Pass
9	Die Shear	Mil-Std-883 M2019.8 / Subcon specs.	-	16	Pass
10	Solderability	JESD22-B102 / Subcon specs.	-	40	Pass

Technology Reliability Report (DOC-87869)

pSemi Confidential